FORTGG

FORTGG probes are silicon probes designed for Force Modulation applications. These probes have a medium frequency and spring constant that make them ideally suited to Force Modulation Microscopy, and have Gold coating on both the reflex and tip sides to increase laser signal quality in fluid environments. The Gold-coated tip side also enhances tip functionalization and signal strength in electrical applications.

Tip Specifications

Material: Silicon
Shape: Pyramidal
Height (µm): 14-16
Aspect ratio: 1.5-3.0
ROC (nm): 30

• **Coating**: Au, 30 nm ± 5



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Cantilever Specifications

Material:Silicon Shape :Rectangular Reflex Au, 40 nm \pm coating 5 Parameter Nominal Min Max 3.7 $k \left(N/m \right)$ 1.6 0.6 f (kHz) 61.0 43.0 81.0 225.0 215.0 235.0 Length $(\mu_{\rm m})$ Width (µm) 27.0 22.0 32.0 2.70 Thickness 2. 20 3. 20 $(\mu_{\rm m})$